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Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	1936
Number of Logic Elements/Cells	4598
Total RAM Bits	61952
Number of I/O	352
Number of Gates	52000
Voltage - Supply	3V ~ 3.6V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	560-LBGA Exposed Pad, Metal
Supplier Device Package	560-MBGA (42.5x42.5)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc4052xl-2bg560c

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



Dual-Port Edge-Triggered Mode

In dual-port mode, both the F and G function generators are used to create a single 16x1 RAM array with one write port and two read ports. The resulting RAM array can be read and written simultaneously at two independent addresses. Simultaneous read and write operations at the same address are also supported.

Dual-port mode always has edge-triggered write timing, as shown in Figure 3.

Figure 6 shows a simple model of an XC4000 Series CLB configured as dual-port RAM. One address port, labeled A[3:0], supplies both the read and write address for the F function generator. This function generator behaves the same as a 16x1 single-port edge-triggered RAM array. The RAM output, Single Port Out (SPO), appears at the F function generator output. SPO, therefore, reflects the data at address A[3:0].

The other address port, labeled DPRA[3:0] for Dual Port Read Address, supplies the read address for the G function generator. The write address for the G function generator, however, comes from the address A[3:0]. The output from this 16x1 RAM array, Dual Port Out (DPO), appears at the G function generator output. DPO, therefore, reflects the data at address DPRA[3:0].

Therefore, by using A[3:0] for the write address and DPRA[3:0] for the read address, and reading only the DPO output, a FIFO that can read and write simultaneously is easily generated. Simultaneous access doubles the effective throughput of the FIFO.

The relationships between CLB pins and RAM inputs and outputs for dual-port, edge-triggered mode are shown in Table 6. See Figure 7 on page 16 for a block diagram of a CLB configured in this mode.

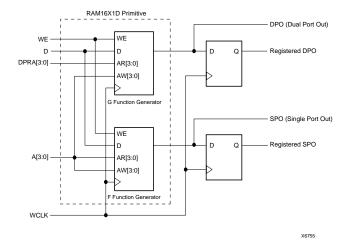


Figure 6: XC4000 Series Dual-Port RAM, Simple Model

Table 6: Dual-Port Edge-Triggered RAM Signals

RAM Signal	CLB Pin	Function
D	D0	Data In
A[3:0]	F1-F4	Read Address for F,
		Write Address for F and G
DPRA[3:0]	G1-G4	Read Address for G
WE	WE	Write Enable
WCLK	K	Clock
SPO	F'	Single Port Out
		(addressed by A[3:0])
DPO	G'	Dual Port Out
		(addressed by DPRA[3:0])

Note: The pulse following the active edge of WCLK (T_{WPS} in Figure 3) must be less than one millisecond wide. For most applications, this requirement is not overly restrictive; however, it must not be forgotten. Stopping WCLK at this point in the write cycle could result in excessive current and even damage to the larger devices if many CLBs are configured as edge-triggered RAM.

Single-Port Level-Sensitive Timing Mode

Note: Edge-triggered mode is recommended for all new designs. Level-sensitive mode, also called asynchronous mode, is still supported for XC4000 Series backward-compatibility with the XC4000 family.

Level-sensitive RAM timing is simple in concept but can be complicated in execution. Data and address signals are presented, then a positive pulse on the write enable pin (WE) performs a write into the RAM at the designated address. As indicated by the "level-sensitive" label, this RAM acts like a latch. During the WE High pulse, changing the data lines results in new data written to the old address. Changing the address lines while WE is High results in spurious data written to the new address—and possibly at other addresses as well, as the address lines inevitably do not all change simultaneously.

The user must generate a carefully timed WE signal. The delay on the WE signal and the address lines must be carefully verified to ensure that WE does not become active until after the address lines have settled, and that WE goes inactive before the address lines change again. The data must be stable before and after the falling edge of WE.

In practical terms, WE is usually generated by a 2X clock. If a 2X clock is not available, the falling edge of the system clock can be used. However, there are inherent risks in this approach, since the WE pulse must be guaranteed inactive before the next rising edge of the system clock. Several older application notes are available from Xilinx that discuss the design of level-sensitive RAMs.

However, the edge-triggered RAM available in the XC4000 Series is superior to level-sensitive RAM for almost every application.



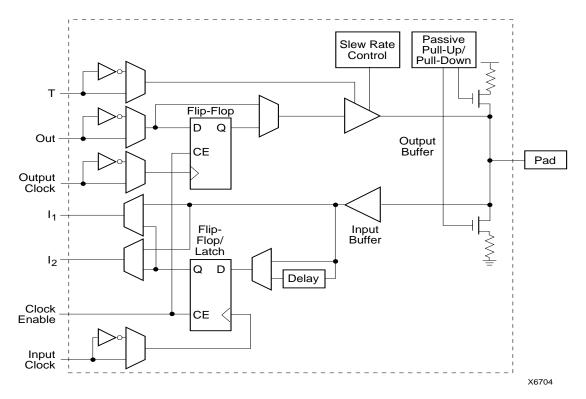


Figure 15: Simplified Block Diagram of XC4000E IOB

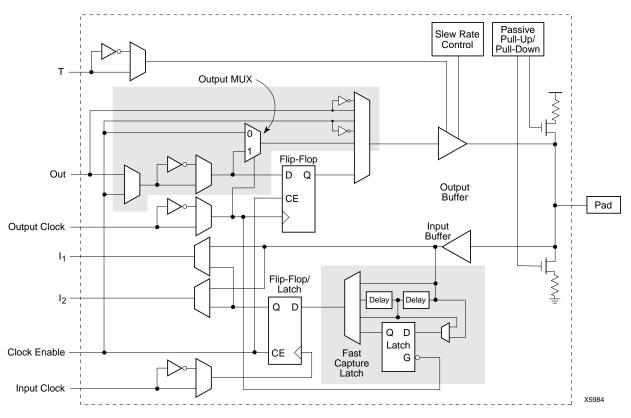


Figure 16: Simplified Block Diagram of XC4000X IOB (shaded areas indicate differences from XC4000E)

Table 8: Supported Sources for XC4000 Series Device Inputs

		00E/EX Inputs	XC4000XL Series Inputs
Source	5 V, TTL	5 V, CMOS	3.3 V CMOS
Any device, Vcc = 3.3 V, CMOS outputs	V	Unreli	√
XC4000 Series, Vcc = 5 V, TTL outputs	V	-able Data	V
Any device, $Vcc = 5 \text{ V}$, TTL outputs $(Voh \le 3.7 \text{ V})$	√	Data	√
Any device, Vcc = 5 V, CMOS outputs	V	√	√

XC4000XL 5-Volt Tolerant I/Os

The I/Os on the XC4000XL are fully 5-volt tolerant even though the $V_{\rm CC}$ is 3.3 volts. This allows 5 V signals to directly connect to the XC4000XL inputs without damage, as shown in Table 8. In addition, the 3.3 volt $V_{\rm CC}$ can be applied before or after 5 volt signals are applied to the I/Os. This makes the XC4000XL immune to power supply sequencing problems.

Registered Inputs

The I1 and I2 signals that exit the block can each carry either the direct or registered input signal.

The input and output storage elements in each IOB have a common clock enable input, which, through configuration, can be activated individually for the input or output flip-flop, or both. This clock enable operates exactly like the EC pin on the XC4000 Series CLB. It cannot be inverted within the IOB.

The storage element behavior is shown in Table 9.

Table 9: Input Register Functionality (active rising edge is shown)

Mode	Clock	Clock Enable	D	Q
Power-Up or GSR	X	X	Х	SR
Flip-Flop		1*	D	D
	0	Х	Х	Q
Latch	1	1*	Х	Q
	0	1*	D	D
Both	Χ	0	Х	Q

Legend:

X Don't care
Rising edge

SR Set or Reset value. Reset is default.

0* Input is Low or unconnected (default value)
1* Input is High or unconnected (default value)

Optional Delay Guarantees Zero Hold Time

The data input to the register can optionally be delayed by several nanoseconds. With the delay enabled, the setup time of the input flip-flop is increased so that normal clock routing does not result in a positive hold-time requirement. A positive hold time requirement can lead to unreliable, temperature- or processing-dependent operation.

The input flip-flop setup time is defined between the data measured at the device I/O pin and the clock input at the IOB (not at the clock pin). Any routing delay from the device clock pin to the clock input of the IOB must, therefore, be subtracted from this setup time to arrive at the real setup time requirement relative to the device pins. A short specified setup time might, therefore, result in a negative setup time at the device pins, i.e., a positive hold-time requirement.

When a delay is inserted on the data line, more clock delay can be tolerated without causing a positive hold-time requirement. Sufficient delay eliminates the possibility of a data hold-time requirement at the external pin. The maximum delay is therefore inserted as the default.

The XC4000E IOB has a one-tap delay element: either the delay is inserted (default), or it is not. The delay guarantees a zero hold time with respect to clocks routed through any of the XC4000E global clock buffers. (See "Global Nets and Buffers (XC4000E only)" on page 35 for a description of the global clock buffers in the XC4000E.) For a shorter input register setup time, with non-zero hold, attach a NODELAY attribute or property to the flip-flop.

The XC4000X IOB has a two-tap delay element, with choices of a full delay, a partial delay, or no delay. The attributes or properties used to select the desired delay are shown in Table 10. The choices are no added attribute, MEDDELAY, and NODELAY. The default setting, with no added attribute, ensures no hold time with respect to any of the XC4000X clock buffers, including the Global Low-Skew buffers. MEDDELAY ensures no hold time with respect to the Global Early buffers. Inputs with NODELAY may have a positive hold time with respect to all clock buffers. For a description of each of these buffers, see "Global Nets and Buffers (XC4000X only)" on page 37.

Table 10: XC4000X IOB Input Delay Element

Value	When to Use
full delay	Zero Hold with respect to Global
(default, no	Low-Skew Buffer, Global Early Buffer
attribute added)	
MEDDELAY	Zero Hold with respect to Global Early
	Buffer
NODELAY	Short Setup, positive Hold time



Additional Input Latch for Fast Capture (XC4000X only)

The XC4000X IOB has an additional optional latch on the input. This latch, as shown in Figure 16, is clocked by the output clock — the clock used for the output flip-flop — rather than the input clock. Therefore, two different clocks can be used to clock the two input storage elements. This additional latch allows the very fast capture of input data, which is then synchronized to the internal clock by the IOB flip-flop or latch.

To use this Fast Capture technique, drive the output clock pin (the Fast Capture latching signal) from the output of one of the Global Early buffers supplied in the XC4000X. The second storage element should be clocked by a Global Low-Skew buffer, to synchronize the incoming data to the internal logic. (See Figure 17.) These special buffers are described in "Global Nets and Buffers (XC4000X only)" on page 37.

The Fast Capture latch (FCL) is designed primarily for use with a Global Early buffer. For Fast Capture, a single clock signal is routed through both a Global Early buffer and a Global Low-Skew buffer. (The two buffers share an input pad.) The Fast Capture latch is clocked by the Global Early buffer, and the standard IOB flip-flop or latch is clocked by the Global Low-Skew buffer. This mode is the safest way to use the Fast Capture latch, because the clock buffers on both storage elements are driven by the same pad. There is no external skew between clock pads to create potential problems.

To place the Fast Capture latch in a design, use one of the special library symbols, ILFFX or ILFLX. ILFFX is a transparent-Low Fast Capture latch followed by an active-High input flip-flop. ILFLX is a transparent-Low Fast Capture latch followed by a transparent-High input latch. Any of the clock inputs can be inverted before driving the library element, and the inverter is absorbed into the IOB. If a single BUFG output is used to drive both clock inputs, the software automatically runs the clock through both a Global Low-Skew buffer and a Global Early buffer, and clocks the Fast Capture latch appropriately.

Figure 16 on page 21 also shows a two-tap delay on the input. By default, if the Fast Capture latch is used, the Xilinx software assumes a Global Early buffer is driving the clock, and selects MEDDELAY to ensure a zero hold time. Select

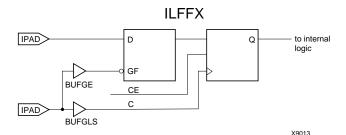


Figure 17: Examples Using XC4000X FCL

the desired delay based on the discussion in the previous subsection.

IOB Output Signals

Output signals can be optionally inverted within the IOB, and can pass directly to the pad or be stored in an edge-triggered flip-flop. The functionality of this flip-flop is shown in Table 11.

An active-High 3-state signal can be used to place the output buffer in a high-impedance state, implementing 3-state outputs or bidirectional I/O. Under configuration control, the output (OUT) and output 3-state (T) signals can be inverted. The polarity of these signals is independently configured for each IOB.

The 4-mA maximum output current specification of many FPGAs often forces the user to add external buffers, which are especially cumbersome on bidirectional I/O lines. The XC4000E and XC4000EX/XL devices solve many of these problems by providing a guaranteed output sink current of 12 mA. Two adjacent outputs can be interconnected externally to sink up to 24 mA. The XC4000E and XC4000EX/XL FPGAs can thus directly drive buses on a printed circuit board.

By default, the output pull-up structure is configured as a TTL-like totem-pole. The High driver is an n-channel pull-up transistor, pulling to a voltage one transistor threshold below Vcc. Alternatively, the outputs can be globally configured as CMOS drivers, with p-channel pull-up transistors pulling to Vcc. This option, applied using the bitstream generation software, applies to all outputs on the device. It is not individually programmable. In the XC4000XL, all outputs are pulled to the positive supply rail.

Table 11: Output Flip-Flop Functionality (active rising edge is shown)

Mode	Clock	Clock Enable	Т	D	Q
Power-Up or GSR	Х	Х	0*	Х	SR
	Х	0	0*	Х	Q
Flip-Flop	/_	1*	0*	D	D
	Х	Х	1	Х	Z
	0	Х	0*	Х	Q

Legend:

X Don't care
Rising edge

SR Set or Reset value. Reset is default.

0* Input is Low or unconnected (default value)
1* Input is High or unconnected (default value)

7 3-state

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or clear on reset and after configuration. Other than the global GSR net, no user-controlled set/reset signal is available to the I/O flip-flops. The choice of set or clear applies to both the initial state of the flip-flop and the response to the Global Set/Reset pulse. See "Global Set/Reset" on page 11 for a description of how to use GSR.

JTAG Support

Embedded logic attached to the IOBs contains test structures compatible with IEEE Standard 1149.1 for boundary scan testing, permitting easy chip and board-level testing. More information is provided in "Boundary Scan" on page 42.

Three-State Buffers

A pair of 3-state buffers is associated with each CLB in the array. (See Figure 27 on page 30.) These 3-state buffers can be used to drive signals onto the nearest horizontal longlines above and below the CLB. They can therefore be used to implement multiplexed or bidirectional buses on the horizontal longlines, saving logic resources. Programmable pull-up resistors attached to these longlines help to implement a wide wired-AND function.

The buffer enable is an active-High 3-state (i.e. an active-Low enable), as shown in Table 13.

Another 3-state buffer with similar access is located near each I/O block along the right and left edges of the array. (See Figure 33 on page 34.)

The horizontal longlines driven by the 3-state buffers have a weak keeper at each end. This circuit prevents undefined floating levels. However, it is overridden by any driver, even a pull-up resistor.

Special longlines running along the perimeter of the array can be used to wire-AND signals coming from nearby IOBs or from internal longlines. These longlines form the wide edge decoders discussed in "Wide Edge Decoders" on page 27.

Three-State Buffer Modes

The 3-state buffers can be configured in three modes:

- · Standard 3-state buffer
- Wired-AND with input on the I pin
- Wired OR-AND

Standard 3-State Buffer

All three pins are used. Place the library element BUFT. Connect the input to the I pin and the output to the O pin. The T pin is an active-High 3-state (i.e. an active-Low enable). Tie the T pin to Ground to implement a standard buffer.

Wired-AND with Input on the I Pin

The buffer can be used as a Wired-AND. Use the WAND1 library symbol, which is essentially an open-drain buffer. WAND4, WAND8, and WAND16 are also available. See the *XACT Libraries Guide* for further information.

The T pin is internally tied to the I pin. Connect the input to the I pin and the output to the O pin. Connect the outputs of all the WAND1s together and attach a PULLUP symbol.

Wired OR-AND

The buffer can be configured as a Wired OR-AND. A High level on either input turns off the output. Use the WOR2AND library symbol, which is essentially an open-drain 2-input OR gate. The two input pins are functionally equivalent. Attach the two inputs to the I0 and I1 pins and tie the output to the O pin. Tie the outputs of all the WOR2ANDs together and attach a PULLUP symbol.

Three-State Buffer Examples

Figure 21 shows how to use the 3-state buffers to implement a wired-AND function. When all the buffer inputs are High, the pull-up resistor(s) provide the High output.

Figure 22 shows how to use the 3-state buffers to implement a multiplexer. The selection is accomplished by the buffer 3-state signal.

Pay particular attention to the polarity of the T pin when using these buffers in a design. Active-High 3-state (T) is identical to an active-Low output enable, as shown in Table 13.

Table 13: Three-State Buffer Functionality

IN	Т	OUT
X	1	Z
IN	0	IN

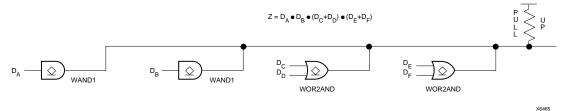


Figure 21: Open-Drain Buffers Implement a Wired-AND Function



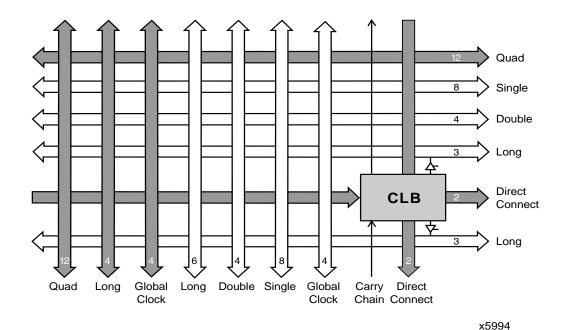


Figure 25: High-Level Routing Diagram of XC4000 Series CLB (shaded arrows indicate XC4000X only)

Table 14: Routing per CLB in XC4000 Series Devices

	XC4	1000E	XC	4000X
	Vertical	Horizontal	Vertical	Horizontal
Singles	8	8	8	8
Doubles	4	4	4	4
Quads	0	0	12	12
Longlines	6	6	10	6
Direct	0	0	2	2
Connects				
Globals	4	0	8	0
Carry Logic	2	0	1	0
Total	24	18	45	32

Programmable Switch Matrices

The horizontal and vertical single- and double-length lines intersect at a box called a programmable switch matrix (PSM). Each switch matrix consists of programmable pass transistors used to establish connections between the lines (see Figure 26).

For example, a single-length signal entering on the right side of the switch matrix can be routed to a single-length line on the top, left, or bottom sides, or any combination thereof, if multiple branches are required. Similarly, a double-length signal can be routed to a double-length line on any or all of the other three edges of the programmable switch matrix.

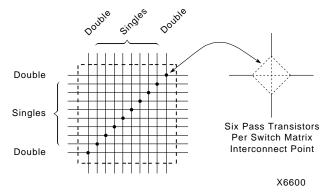


Figure 26: Programmable Switch Matrix (PSM)

Single-Length Lines

Single-length lines provide the greatest interconnect flexibility and offer fast routing between adjacent blocks. There are eight vertical and eight horizontal single-length lines associated with each CLB. These lines connect the switching matrices that are located in every row and a column of CLBs.

Single-length lines are connected by way of the programmable switch matrices, as shown in Figure 28. Routing connectivity is shown in Figure 27.

Single-length lines incur a delay whenever they go through a switching matrix. Therefore, they are not suitable for routing signals for long distances. They are normally used to conduct signals within a localized area and to provide the branching for nets with fanout greater than one.



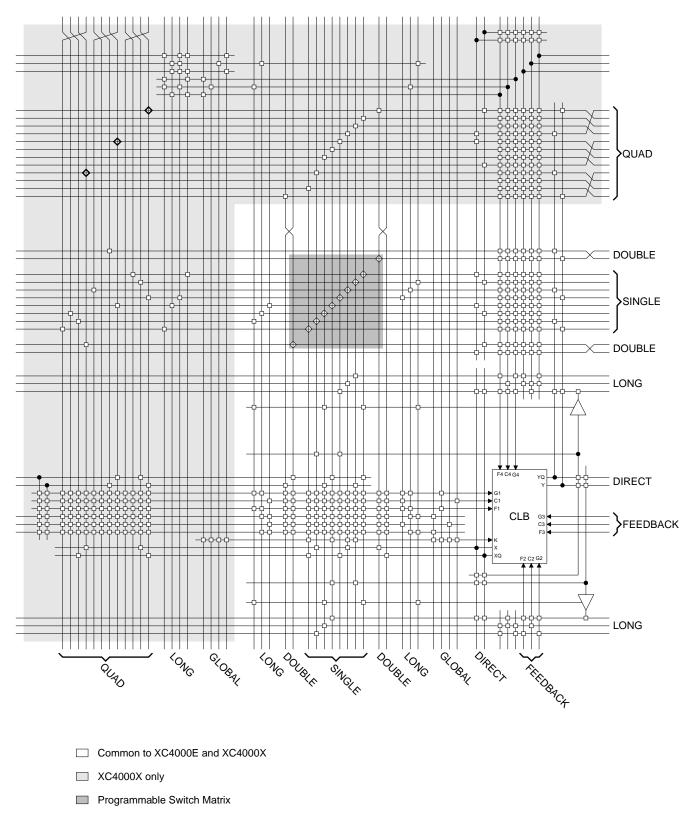


Figure 27: Detail of Programmable Interconnect Associated with XC4000 Series CLB

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circuit prevents undefined floating levels. However, it is overridden by any driver, even a pull-up resistor.

Each XC4000E longline has a programmable splitter switch at its center, as does each XC4000X longline driven by TBUFs. This switch can separate the line into two independent routing channels, each running half the width or height of the array.

Each XC4000X longline not driven by TBUFs has a buffered programmable splitter switch at the 1/4, 1/2, and 3/4 points of the array. Due to the buffering, XC4000X longline performance does not deteriorate with the larger array sizes. If the longline is split, the resulting partial longlines are independent.

Routing connectivity of the longlines is shown in Figure 27 on page 30.

Direct Interconnect (XC4000X only)

The XC4000X offers two direct, efficient and fast connections between adjacent CLBs. These nets facilitate a data flow from the left to the right side of the device, or from the top to the bottom, as shown in Figure 30. Signals routed on the direct interconnect exhibit minimum interconnect propagation delay and use no general routing resources.

The direct interconnect is also present between CLBs and adjacent IOBs. Each IOB on the left and top device edges has a direct path to the nearest CLB. Each CLB on the right and bottom edges of the array has a direct path to the nearest two IOBs, since there are two IOBs for each row or column of CLBs.

The place and route software uses direct interconnect whenever possible, to maximize routing resources and minimize interconnect delays.

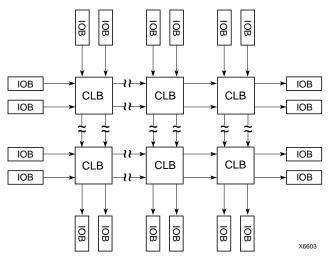


Figure 30: XC4000X Direct Interconnect

I/O Routing

XC4000 Series devices have additional routing around the IOB ring. This routing is called a VersaRing. The VersaRing facilitates pin-swapping and redesign without affecting board layout. Included are eight double-length lines spanning two CLBs (four IOBs), and four longlines. Global lines and Wide Edge Decoder lines are provided. XC4000X devices also include eight octal lines.

A high-level diagram of the VersaRing is shown in Figure 31. The shaded arrows represent routing present only in XC4000X devices.

Figure 33 on page 34 is a detailed diagram of the XC4000E and XC4000X VersaRing. The area shown includes two IOBs. There are two IOBs per CLB row or column, therefore this diagram corresponds to the CLB routing diagram shown in Figure 27 on page 30. The shaded areas represent routing and routing connections present only in XC4000X devices.

Octal I/O Routing (XC4000X only)

Between the XC4000X CLB array and the pad ring, eight interconnect tracks provide for versatility in pin assignment and fixed pinout flexibility. (See Figure 32 on page 33.)

These routing tracks are called octals, because they can be broken every eight CLBs (sixteen IOBs) by a programmable buffer that also functions as a splitter switch. The buffers are staggered, so each line goes through a buffer at every eighth CLB location around the device edge.

The octal lines bend around the corners of the device. The lines cross at the corners in such a way that the segment most recently buffered before the turn has the farthest distance to travel before the next buffer, as shown in Figure 32.

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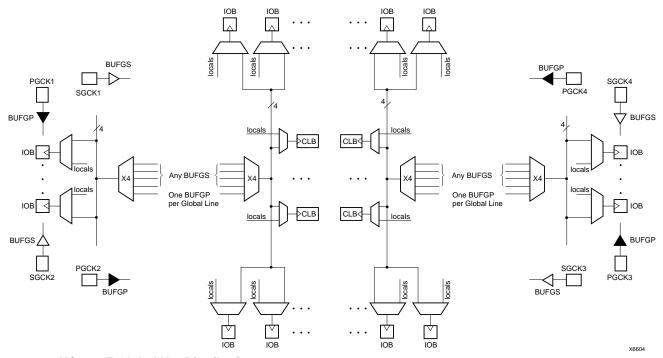


Figure 34: XC4000E Global Net Distribution

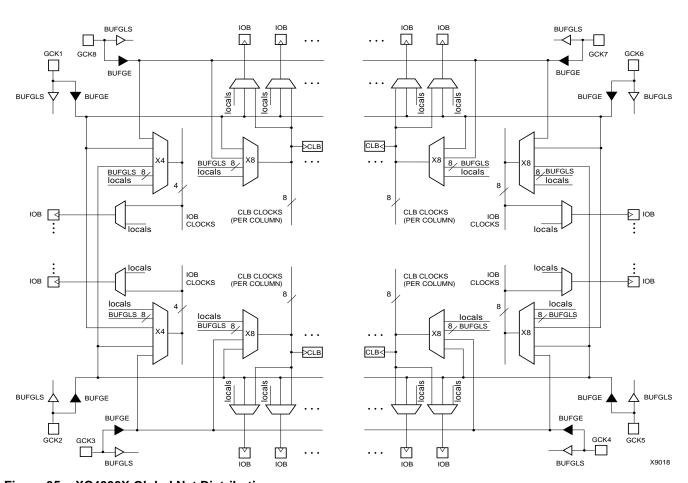


Figure 35: XC4000X Global Net Distribution

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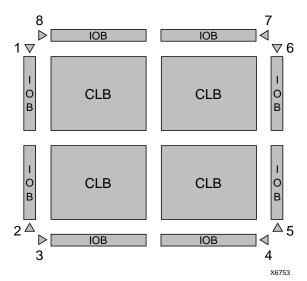


Figure 36: Any BUFGLS (GCK1 - GCK8) Can Drive Any or All Clock Inputs on the Device

Global Early Buffers

Each corner of the XC4000X device has two Global Early buffers. The primary purpose of the Global Early buffers is to provide an earlier clock access than the potentially heavily-loaded Global Low-Skew buffers. A clock source applied to both buffers will result in the Global Early clock edge occurring several nanoseconds earlier than the Global Low-Skew buffer clock edge, due to the lighter loading.

Global Early buffers also facilitate the fast capture of device inputs, using the Fast Capture latches described in "IOB Input Signals" on page 20. For Fast Capture, take a single clock signal, and route it through both a Global Early buffer and a Global Low-Skew buffer. (The two buffers share an input pad.) Use the Global Early buffer to clock the Fast Capture latch, and the Global Low-Skew buffer to clock the normal input flip-flop or latch, as shown in Figure 17 on page 23.

The Global Early buffers can also be used to provide a fast Clock-to-Out on device output pins. However, an early clock in the output flip-flop IOB must be taken into consideration when calculating the internal clock speed for the design.

The Global Early buffers at the left and right edges of the chip have slightly different capabilities than the ones at the top and bottom. Refer to Figure 37, Figure 38, and Figure 35 on page 36 while reading the following explanation.

Each Global Early buffer can access the eight vertical Global lines for all CLBs in the quadrant. Therefore, only one-fourth of the CLB clock pins can be accessed. This restriction is in large part responsible for the faster speed of the buffers, relative to the Global Low-Skew buffers.

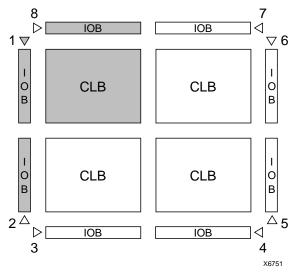


Figure 37: Left and Right BUFGEs Can Drive Any or All Clock Inputs in Same Quadrant or Edge (GCK1 is shown. GCK2, GCK5 and GCK6 are similar.)

The left-side Global Early buffers can each drive two of the four vertical lines accessing the IOBs on the entire left edge of the device. The right-side Global Early buffers can each drive two of the eight vertical lines accessing the IOBs on the entire right edge of the device. (See Figure 37.)

Each left and right Global Early buffer can also drive half of the IOBs along either the top or bottom edge of the device, using a dedicated line that can only be accessed through the Global Early buffers.

The top and bottom Global Early buffers can drive half of the IOBs along either the left or right edge of the device, as shown in Figure 38. They can only access the top and bottom IOBs via the CLB global lines.

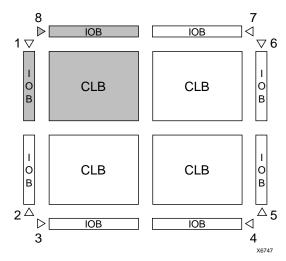


Figure 38: Top and Bottom BUFGEs Can Drive Any or All Clock Inputs in Same Quadrant (GCK8 is shown. GCK3, GCK4 and GCK7 are similar.)



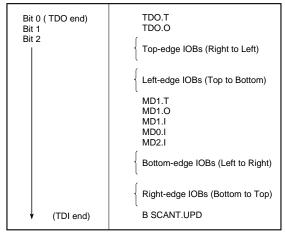
Table 16: Pin Descriptions (Continued)

	I/O During	I/O After	
Pin Name	Config.	Config.	Pin Description
TDI, TCK, TMS	I	I/O or I (JTAG)	If boundary scan is used, these pins are Test Data In, Test Clock, and Test Mode Select inputs respectively. They come directly from the pads, bypassing the IOBs. These pins can also be used as inputs to the CLB logic after configuration is completed. If the BSCAN symbol is not placed in the design, all boundary scan functions are inhibited once configuration is completed, and these pins become user-programmable I/O. The pins can be used automatically or user-constrained. To use them, use "LOC=" or place the library components TDI, TCK, and TMS instead of the usual pad symbols. Input or output buffers must still be used.
HDC	0	I/O	High During Configuration (HDC) is driven High until the I/O go active. It is available as a control output indicating that configuration is not yet completed. After configuration, HDC is a user-programmable I/O pin.
LDC	0	I/O	Low During Configuration (LDC) is driven Low until the I/O go active. It is available as a control output indicating that configuration is not yet completed. After configuration, LDC is a user-programmable I/O pin.
ĪNIT	I/O	I/O	Before and during configuration, $\overline{\text{INIT}}$ is a bidirectional signal. A 1 k Ω - 10 k Ω external pull-up resistor is recommended. As an active-Low open-drain output, $\overline{\text{INIT}}$ is held Low during the power stabilization and internal clearing of the configuration memory. As an active-Low input, it can be used to hold the FPGA in the internal WAIT state before the start of configuration. Master mode devices stay in a WAIT state an additional 30 to 300 μ s after $\overline{\text{INIT}}$ has gone High. During configuration, a Low on this output indicates that a configuration data error has occurred. After the I/O go active, $\overline{\text{INIT}}$ is a user-programmable I/O pin.
PGCK1 - PGCK4 (XC4000E only)	Weak Pull-up	I or I/O	Four Primary Global inputs each drive a dedicated internal global net with short delay and minimal skew. If not used to drive a global buffer, any of these pins is a user-programmable I/O. The PGCK1-PGCK4 pins drive the four Primary Global Buffers. Any input pad symbol connected directly to the input of a BUFGP symbol is automatically placed on one of these pins.
SGCK1 - SGCK4 (XC4000E only)	Weak Pull-up	I or I/O	Four Secondary Global inputs each drive a dedicated internal global net with short delay and minimal skew. These internal global nets can also be driven from internal logic. If not used to drive a global net, any of these pins is a user-programmable I/O pin. The SGCK1-SGCK4 pins provide the shortest path to the four Secondary Global Buffers. Any input pad symbol connected directly to the input of a BUFGS symbol is automatically placed on one of these pins.
GCK1 - GCK8 (XC4000X only)	Weak Pull-up	I or I/O	Eight inputs can each drive a Global Low-Skew buffer. In addition, each can drive a Global Early buffer. Each pair of global buffers can also be driven from internal logic, but must share an input signal. If not used to drive a global buffer, any of these pins is a user-programmable I/O. Any input pad symbol connected directly to the input of a BUFGLS or BUFGE symbol is automatically placed on one of these pins.
FCLK1 - FCLK4 (XC4000XLA and XC4000XV only)	Weak Pull-up	I or I/O	Four inputs can each drive a Fast Clock (FCLK) buffer which can deliver a clock signal to any IOB clock input in the octant of the die served by the Fast Clock buffer. Two Fast Clock buffers serve the two IOB octants on the left side of the die and the other two Fast Clock buffers serve the two IOB octants on the right side of the die. On each side of the die, one Fast Clock buffer serves the upper octant and the other serves the lower octant. If not used to drive a Fast Clock buffer, any of these pins is a user-programmable I/O.



Table 17: Boundary Scan Instructions

	uction		Test Selected	TDO Source	I/O Data Source
0	0	0	EXTEST	DR	DR
0	0	1	SAMPLE/PR ELOAD	DR	Pin/Logic
0	1	0	USER 1	BSCAN. TDO1	User Logic
0	1	1	USER 2	BSCAN. TDO2	User Logic
1	0	0	READBACK	Readback Data	Pin/Logic
1	0	1	CONFIGURE	DOUT	Disabled
1	1	0	Reserved		
1	1	1	BYPASS	Bypass Register	_



X6075

Figure 42: Boundary Scan Bit Sequence

Avoiding Inadvertent Boundary Scan

If TMS or TCK is used as user I/O, care must be taken to ensure that at least one of these pins is held constant during configuration. In some applications, a situation may occur where TMS or TCK is driven during configuration. This may cause the device to go into boundary scan mode and disrupt the configuration process.

To prevent activation of boundary scan during configuration, do either of the following:

- TMS: Tie High to put the Test Access Port controller in a benign RESET state
- TCK: Tie High or Low—don't toggle this clock input.

For more information regarding boundary scan, refer to the Xilinx Application Note XAPP 017.001, "Boundary Scan in XC4000E Devices."

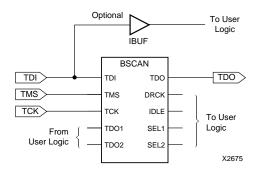


Figure 43: Boundary Scan Schematic Example

Configuration

Configuration is the process of loading design-specific programming data into one or more FPGAs to define the functional operation of the internal blocks and their interconnections. This is somewhat like loading the command registers of a programmable peripheral chip. XC4000 Series devices use several hundred bits of configuration data per CLB and its associated interconnects. Each configuration bit defines the state of a static memory cell that controls either a function look-up table bit, a multiplexer input, or an interconnect pass transistor. The XACT step development system translates the design into a netlist file. It automatically partitions, places and routes the logic and generates the configuration data in PROM format.

Special Purpose Pins

Three configuration mode pins (M2, M1, M0) are sampled prior to configuration to determine the configuration mode. After configuration, these pins can be used as auxiliary connections. M2 and M0 can be used as inputs, and M1 can be used as an output. The XACT step development system does not use these resources unless they are explicitly specified in the design entry. This is done by placing a special pad symbol called MD2, MD1, or MD0 instead of the input or output pad symbol.

In XC4000 Series devices, the mode pins have weak pull-up resistors during configuration. With all three mode pins High, Slave Serial mode is selected, which is the most popular configuration mode. Therefore, for the most common configuration mode, the mode pins can be left unconnected. (Note, however, that the internal pull-up resistor value can be as high as 100 k Ω .) After configuration, these pins can individually have weak pull-up or pull-down resistors, as specified in the design. A pull-down resistor value of 4.7 k Ω is recommended.

These pins are located in the lower left chip corner and are near the readback nets. This location allows convenient routing if compatibility with the XC2000 and XC3000 family conventions of M0/RT, M1/RD is desired.

Product Obsolete or Under Obsolescence XC4000E and XC4000X Series Field Programmable Gate Arrays

is passed through and is captured by each FPGA when it recognizes the 0010 preamble. Following the length-count data, each FPGA outputs a High on DOUT until it has received its required number of data frames.

After an FPGA has received its configuration data, it passes on any additional frame start bits and configuration data on DOUT. When the total number of configuration clocks applied after memory initialization equals the value of the 24-bit length count, the FPGAs begin the start-up sequence and become operational together. FPGA I/O are normally released two CCLK cycles after the last configuration bit is received. Figure 47 on page 53 shows the start-up timing for an XC4000 Series device.

The daisy-chained bitstream is not simply a concatenation of the individual bitstreams. The PROM file formatter must be used to combine the bitstreams for a daisy-chained configuration.

Multi-Family Daisy Chain

All Xilinx FPGAs of the XC2000, XC3000, and XC4000 Series use a compatible bitstream format and can, therefore, be connected in a daisy chain in an arbitrary sequence. There is, however, one limitation. The lead device must belong to the highest family in the chain. If the chain contains XC4000 Series devices, the master normally cannot be an XC2000 or XC3000 device.

The reason for this rule is shown in Figure 47 on page 53. Since all devices in the chain store the same length count value and generate or receive one common sequence of CCLK pulses, they all recognize length-count match on the same CCLK edge, as indicated on the left edge of Figure 47. The master device then generates additional CCLK pulses until it reaches its finish point F. The different families generate or require different numbers of additional CCLK pulses until they reach F. Not reaching F means that the device does not really finish its configuration, although DONE may have gone High, the outputs became active, and the internal reset was released. For the XC4000 Series device, not reaching F means that readback cannot be ini-

tiated and most boundary scan instructions cannot be used.

The user has some control over the relative timing of these events and can, therefore, make sure that they occur at the proper time and the finish point F is reached. Timing is controlled using options in the bitstream generation software.

XC3000 Master with an XC4000 Series Slave

Some designers want to use an inexpensive lead device in peripheral mode and have the more precious I/O pins of the XC4000 Series devices all available for user I/O. Figure 44 provides a solution for that case.

This solution requires one CLB, one IOB and pin, and an internal oscillator with a frequency of up to 5 MHz as a clock source. The XC3000 master device must be configured with late Internal Reset, which is the default option.

One CLB and one IOB in the lead XC3000-family device are used to generate the additional CCLK pulse required by the XC4000 Series devices. When the lead device removes the internal RESET signal, the 2-bit shift register responds to its clock input and generates an active Low output signal for the duration of the subsequent clock period. An external connection between this output and CCLK thus creates the extra CCLK pulse.

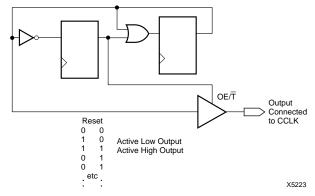


Figure 44: CCLK Generation for XC3000 Master Driving an XC4000 Series Slave



Table 20: XC4000E Program Data

Device	XC4003E	XC4005E	XC4006E	XC4008E	XC4010E	XC4013E	XC4020E	XC4025E
Max Logic Gates	3,000	5,000	6,000	8,000	10,000	13,000	20,000	25,000
CLBs	100	196	256	324	400	576	784	1,024
(Row x Col.)	(10 x 10)	(14 x 14)	(16 x 16)	(18 x 18)	(20 x 20)	(24 x 24)	(28 x 28)	(32 x 32)
IOBs	80	112	128	144	160	192	224	256
Flip-Flops	360	616	768	936	1,120	1,536	2,016	2,560
Bits per Frame	126	166	186	206	226	266	306	346
Frames	428	572	644	716	788	932	1,076	1,220
Program Data	53,936	94,960	119,792	147,504	178,096	247,920	329,264	422,128
PROM Size (bits)	53,984	95,008	119,840	147,552	178,144	247,968	329,312	422,176

Notes: 1. Bits per Frame = (10 x number of rows) + 7 for the top + 13 for the bottom + 1 + 1 start bit + 4 error check bits

Number of Frames = (36 x number of columns) + 26 for the left edge + 41 for the right edge + 1

Program Data = (Bits per Frame x Number of Frames) + 8 postamble bits

PROM Size = Program Data + 40 (header) + 8

2. The user can add more "one" bits as leading dummy bits in the header, or, if CRC = off, as trailing dummy bits at the end of any frame, following the four error check bits. However, the Length Count value must be adjusted for all such extra "one" bits, even for extra leading ones at the beginning of the header.

Table 21: XC4000EX/XL Program Data

Device	XC4002XL	XC4005	XC4010	XC4013	XC4020	XC4028	XC4036	XC4044	XC4052	XC4062	XC4085
Max Logic Gates	2,000	5,000	10,000	13,000	20,000	28,000	36,000	44,000	52,000	62,000	85,000
CLBs (Row x Column)	64 (8 x 8)	196 (14 x 14)	400 (20 x 20)	576 (24 x 24)	784 (28 x 28)	1,024 (32 x 32)	1,296 (36 x 36)	1,600 (40 x 40)	1,936 (44 x 44)	2,304 (48 x 48)	3,136 (56 x 56)
IOBs	64	112	160	192	224	256	288	320	352	384	448
Flip-Flops	256	616	1,120	1,536	2,016	2,560	3,168	3,840	4,576	5,376	7,168
Bits per Frame	133	205	277	325	373	421	469	517	565	613	709
Frames	459	741	1,023	1,211	1,399	1,587	1,775	1,963	2,151	2,339	2,715
Program Data	61,052	151,910	283,376	393,580	521,832	668,124	832,480	1,014,876	1,215,320	1,433,804	1,924,940
PROM Size (bits)	61,104	151,960	283,424	393,632	521,880	668,172	832,528	1,014,924	1,215,368	1,433,852	1,924,992

Notes: 1. Bits per frame = (13 x number of rows) + 9 for the top + 17 for the bottom + 8 + 1 start bit + 4 error check bits. Frames = (47 x number of columns) + 27 for the left edge + 52 for the right edge + 4.

Program data = (bits per frame x number of frames) + 5 postamble bits.

PROM size = (program data + 40 header bits + 8 start bits) rounded up to the nearest byte.

2. The user can add more "one" bits as leading dummy bits in the header, or, if CRC = off, as trailing dummy bits at the end of any frame, following the four error check bits. However, the Length Count value must be adjusted for all such extra "one" bits, even for extra leading "ones" at the beginning of the header.

Cyclic Redundancy Check (CRC) for Configuration and Readback

The Cyclic Redundancy Check is a method of error detection in data transmission applications. Generally, the transmitting system performs a calculation on the serial bitstream. The result of this calculation is tagged onto the data stream as additional check bits. The receiving system performs an identical calculation on the bitstream and compares the result with the received checksum.

Each data frame of the configuration bitstream has four error bits at the end, as shown in Table 19. If a frame data error is detected during the loading of the FPGA, the con-

figuration process with a potentially corrupted bitstream is terminated. The FPGA pulls the $\overline{\text{INIT}}$ pin Low and goes into a Wait state.

During Readback, 11 bits of the 16-bit checksum are added to the end of the Readback data stream. The checksum is computed using the CRC-16 CCITT polynomial, as shown in Figure 45. The checksum consists of the 11 most significant bits of the 16-bit code. A change in the checksum indicates a change in the Readback bitstream. A comparison to a previous checksum is meaningful only if the readback data is independent of the current device state. CLB outputs should not be included (Read Capture option not



used), and if RAM is present, the RAM content must be unchanged.

Statistically, one error out of 2048 might go undetected.

Configuration Sequence

There are four major steps in the XC4000 Series power-up configuration sequence.

- Configuration Memory Clear
- Initialization
- Configuration
- Start-Up

The full process is illustrated in Figure 46.

Configuration Memory Clear

When power is first applied or is reapplied to an FPGA, an internal circuit forces initialization of the configuration logic. When Vcc reaches an operational level, and the circuit passes the write and read test of a sample pair of configuration bits, a time delay is started. This time delay is nominally 16 ms, and up to 10% longer in the low-voltage devices. The delay is four times as long when in Master Modes (M0 Low), to allow ample time for all slaves to reach a stable Vcc. When all $\overline{\text{INIT}}$ pins are tied together, as recommended, the longest delay takes precedence. Therefore, devices with different time delays can easily be mixed and matched in a daisy chain.

This delay is applied only on power-up. It is not applied when re-configuring an FPGA by pulsing the $\overline{\text{PROGRAM}}$ pin

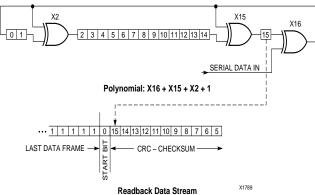


Figure 45: Circuit for Generating CRC-16

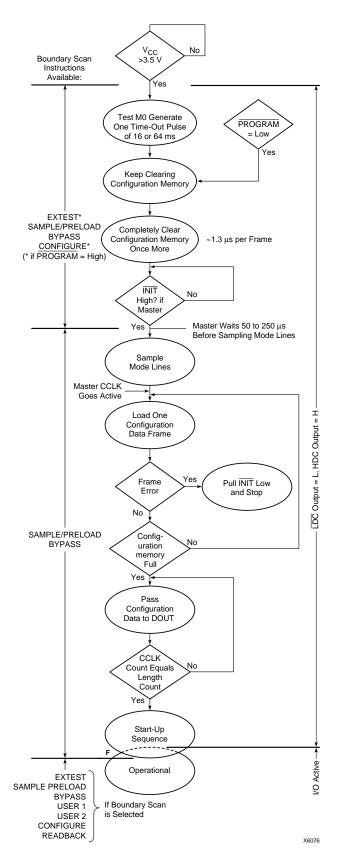


Figure 46: Power-up Configuration Sequence



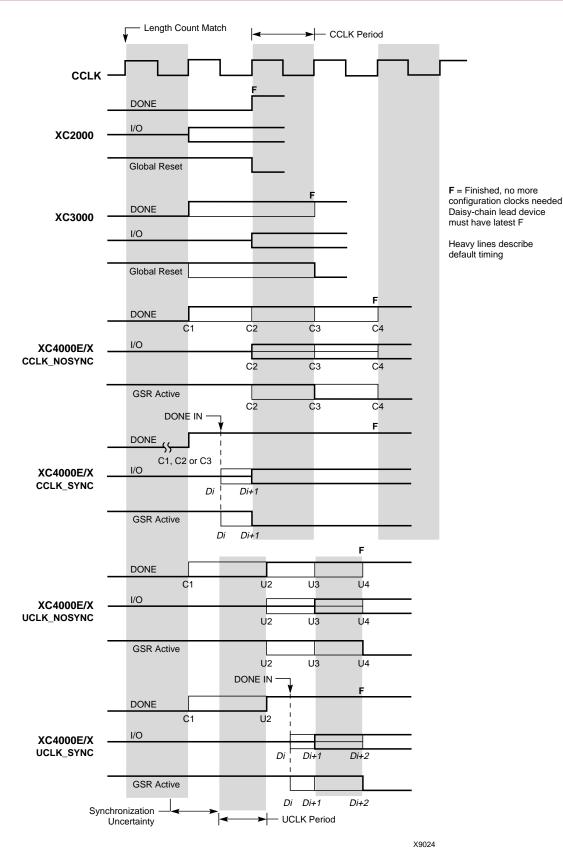


Figure 47: Start-up Timing

Figure 49: Readback Schematic Example

Readback Options

Readback options are: Read Capture, Read Abort, and Clock Select. They are set with the bitstream generation software.

Read Capture

When the Read Capture option is selected, the readback data stream includes sampled values of CLB and IOB signals. The rising edge of RDBK.TRIG latches the inverted values of the four CLB outputs, the IOB output flip-flops and the input signals I1 and I2. Note that while the bits describing configuration (interconnect, function generators, and RAM content) are *not* inverted, the CLB and IOB output signals *are* inverted.

When the Read Capture option is not selected, the values of the capture bits reflect the configuration data originally written to those memory locations.

If the RAM capability of the CLBs is used, RAM data are available in readback, since they directly overwrite the F and G function-table configuration of the CLB.

RDBK.TRIG is located in the lower-left corner of the device, as shown in Figure 50.

Read Abort

When the Read Abort option is selected, a High-to-Low transition on RDBK.TRIG terminates the readback operation and prepares the logic to accept another trigger.

After an aborted readback, additional clocks (up to one readback clock per configuration frame) may be required to re-initialize the control logic. The status of readback is indicated by the output control net RDBK.RIP. RDBK.RIP is High whenever a readback is in progress.

Clock Select

CCLK is the default clock. However, the user can insert another clock on RDBK.CLK. Readback control and data are clocked on rising edges of RDBK.CLK. If readback must be inhibited for security reasons, the readback control nets are simply not connected.

RDBK.CLK is located in the lower right chip corner, as shown in Figure 50.

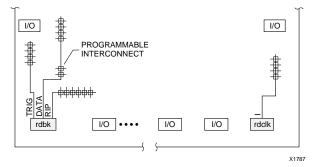


Figure 50: READBACK Symbol in Graphical Editor

Violating the Maximum High and Low Time Specification for the Readback Clock

The readback clock has a maximum High and Low time specification. In some cases, this specification cannot be met. For example, if a processor is controlling readback, an interrupt may force it to stop in the middle of a readback. This necessitates stopping the clock, and thus violating the specification.

The specification is mandatory only on clocking data at the end of a frame prior to the next start bit. The transfer mechanism will load the data to a shift register during the last six clock cycles of the frame, prior to the start bit of the following frame. This loading process is dynamic, and is the source of the maximum High and Low time requirements.

Therefore, the specification only applies to the six clock cycles prior to and including any start bit, including the clocks before the first start bit in the readback data stream. At other times, the frame data is already in the register and the register is not dynamic. Thus, it can be shifted out just like a regular shift register.

The user must precisely calculate the location of the readback data relative to the frame. The system must keep track of the position within a data frame, and disable interrupts before frame boundaries. Frame lengths and data formats are listed in Table 19, Table 20 and Table 21.

Readback with the XChecker Cable

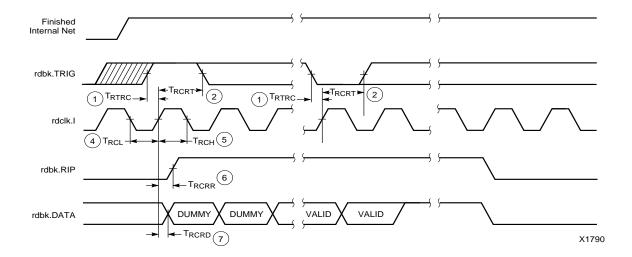
The XChecker Universal Download/Readback Cable and Logic Probe uses the readback feature for bitstream verification. It can also display selected internal signals on the PC or workstation screen, functioning as a low-cost in-circuit emulator.



XC4000E/EX/XL Program Readback Switching Characteristic Guidelines

Testing of the switching parameters is modeled after testing methods specified by MIL-M-38510/605. All devices are 100% functionally tested. Internal timing parameters are not measured directly. They are derived from benchmark timing patterns that are taken at device introduction, prior to any process improvements.

The following guidelines reflect worst-case values over the recommended operating conditions.



E/EX

	Description		Symbol	Min	Max	Units
rdbk.TRIG	rdbk.TRIG setup to initiate and abort Readback	1	T _{RTRC}	200	-	ns
	rdbk.TRIG hold to initiate and abort Readback	2	T _{RCRT}	50	-	ns
rdclk.1	rdbk.DATA delay	7	T _{RCRD}	-	250	ns
	rdbk.RIP delay	6	T _{RCRR}	-	250	ns
	High time	5	T _{RCH}	250	500	ns
	Low time	4	T _{RCL}	250	500	ns

Note 1: Timing parameters apply to all speed grades.

Note 2: If rdbk.TRIG is High prior to Finished, Finished will trigger the first Readback.

XL

	Description		Symbol	Min	Max	Units
rdbk.TRIG	rdbk.TRIG setup to initiate and abort Readback	1	T _{RTRC}	200	-	ns
	rdbk.TRIG hold to initiate and abort Readback	2	T _{RCRT}	50	-	ns
rdclk.1	rdbk.DATA delay	7	T _{RCRD}	-	250	ns
	rdbk.RIP delay	6	T _{RCRR}	-	250	ns
	High time	5	T _{RCH}	250	500	ns
	Low time	4	T _{RCL}	250	500	ns

Note 1: Timing parameters apply to all speed grades.

Note 2: If rdbk.TRIG is High prior to Finished, Finished will trigger the first Readback.



Table 23: Pin Functions During Configuration

SLAVE SERIAL <1:1:1>	MASTER SERIAL <0:0:0>	SYNCH. PERIPHERAL <0:1:1>	<1:0:1> <1:1:0>		MASTER PARALLEL UP <1:0:0>	USER OPERATION	
M2(HIGH) (I)	M2(LOW) (I)	M2(LOW) (I)	M2(HIGH) (I)	M2(HIGH) (I)	M2(HIGH) (I)	(I)	
M1(HIGH) (I)	M1(LOW) (I)	M1(HIGH) (I)	M1(LOW) (I)	M1(HIGH) (I)	M1(LOW) (I)	(O)	
M0(HIGH) (I)	M0(LOW) (I)	M0(HIGH) (I)	M0(HIGH) (I)	M0(LOW) (I)	M0(LOW) (I)	(I)	
HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	I/O	
LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	I/O	
ĪNIT	ĪNIT	ĪNĪT	ĪNIT	ĪNIT	ĪNIT	I/O	
DONE	DONE	DONE	DONE	DONE	DONE	DONE	
PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM	
CCLK (I)	CCLK (O)	CCLK (I)	CCLK (O)	CCLK (O)	CCLK (O)	CCLK (I)	
		RDY/BUSY (O)	RDY/BUSY (O)	RCLK (O)	RCLK (O)	I/O	
			RS (I)			I/O	
			CSO (I)			I/O	
		DATA 7 (I)	DATA 7 (I)	DATA 7 (I)	DATA 7 (I)	I/O	
		DATA 6 (I)	DATA 6 (I)	DATA 6 (I)	DATA 6 (I)	I/O	
		DATA 5 (I)	DATA 5 (I)	DATA 5 (I)	DATA 5 (I)	I/O	
		DATA 4 (I)	DATA 4 (I)	DATA 4 (I)	DATA 4 (I)	I/O	
		DATA 3 (I)	DATA 3 (I)	DATA 3 (I)	DATA 3 (I)	I/O	
		DATA 2 (I)	DATA 2 (I)	DATA 2 (I)	DATA 2 (I)	I/O	
		DATA 1 (I)	DATA 1 (I)	DATA 1 (I)	DATA 1 (I)	I/O	
DIN (I)	DIN (I)	DATA 0 (I)	DATA 0 (I)	DATA 0 (I)	DATA 0 (I)	I/O	
DOUT	DOUT	DOUT	DOUT	DOUT	DOUT	SGCK4-GCK6-I/O	
TDI	TDI	TDI	TDI	TDI	TDI	TDI-I/O	
TCK	TCK	TCK	TCK	TCK	TCK	TCK-I/O	
TMS	TMS	TMS	TMS	TMS	TMS	TMS-I/O	
TDO	TDO	TDO	TDO	TDO	TDO	TDO-(O)	
			WS (I)	A0	A0	I/O	
				A1	A1	PGCK4-GCK7-I/O	
			CS1	A2	A2	I/O	
				A3	A3	I/O	
				A4	A4	I/O	
				A5	A5	I/O	
				A6	A6	I/O	
				A7	A7	I/O	
				A8	A8	I/O	
				A9	A9	I/O	
				A10	A10	I/O	
				A11	A11	I/O	
				A12	A12	I/O	
				A13	A13	I/O	
				A14	A14	I/O	
				A15	A15	SGCK1-GCK8-I/O	
				A16	A16	PGCK1-GCK1-I/O	
				A17	A17	I/O	
				A18*	A18*	I/O	
				A19*	A19*	I/O	
				A20*	A20*	I/O	
				A21*	A21*	I/O	
						ALL OTHERS	

^{*} XC4000X only

Notes 1. A shaded table cell represents a 50 k Ω - 100 k Ω pull-up before and during configuration.

 ⁽I) represents an input; (O) represents an output.
 INIT is an open-drain output during configuration.



Master Serial Mode

In Master Serial mode, the CCLK output of the lead FPGA drives a Xilinx Serial PROM that feeds the FPGA DIN input. Each rising edge of the CCLK output increments the Serial PROM internal address counter. The next data bit is put on the SPROM data output, connected to the FPGA DIN pin. The lead FPGA accepts this data on the subsequent rising CCLK edge.

The lead FPGA then presents the preamble data—and all data that overflows the lead device—on its DOUT pin. There is an internal pipeline delay of 1.5 CCLK periods, which means that DOUT changes on the falling CCLK edge, and the next FPGA in the daisy chain accepts data on the subsequent rising CCLK edge.

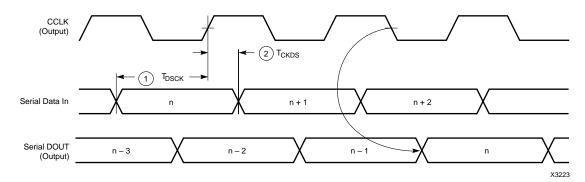
In the bitstream generation software, the user can specify Fast ConfigRate, which, starting several bits into the first frame, increases the CCLK frequency by a factor of eight.

For actual timing values please refer to "Configuration Switching Characteristics" on page 68. Be sure that the serial PROM and slaves are fast enough to support this data rate. XC2000, XC3000/A, and XC3100A devices do not support the Fast ConfigRate option.

The SPROM CE input can be driven from either LDC or DONE. Using LDC avoids potential contention on the DIN pin, if this pin is configured as user-I/O, but LDC is then restricted to be a permanently High user output after configuration. Using DONE can also avoid contention on DIN, provided the early DONE option is invoked.

Figure 51 on page 60 shows a full master/slave system. The leftmost device is in Master Serial mode.

Master Serial mode is selected by a <000> on the mode pins (M2, M1, M0).



	Description	Symbol		Min	Max	Units
CCLK	DIN setup	1	T _{DSCK}	20		ns
	DIN hold	2	T _{CKDS}	0		ns

Notes: 1. At power-up, Vcc must rise from 2.0 V to Vcc min in less than 25 ms, otherwise delay configuration by pulling PROGRAM Low until Vcc is valid.

2. Master Serial mode timing is based on testing in slave mode.

Figure 53: Master Serial Mode Programming Switching Characteristics